



**Part 0: SAR and Power Density Characterization  
EUT RF Exposure Compliance Test Report**

*For*  
**SMARTPHONE**

**FCC ID: BCG-E3994A  
Model Name: A2481**

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*Prepared for*  
**APPLE INC.**  
**1 APPLE PARK WAY**  
**CUPERTINO, CA 95014-2084**

*Prepared by*  
**UL VERIFICATION SERVICES INC.**  
**47173 BENICIA STREET**  
**FREMONT, CA 94538, U.S.A.**  
**TEL: (510) 319-4000**  
**FAX: (510) 661-0888**



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## 1. Introduction

The equipment under test (EUT) is a smart phone. It contains the Qualcomm modem supporting 2G/3G/4G WWAN technologies and mmW 5G NR bands. These WWAN modems enable Qualcomm's Smart Transmit feature to control and manage transmitting power, in real time, and to ensure the time-averaged RF exposure is always in compliance with the FCC requirement.

In this report, Part 0, the EUT SAR and power density (PD) are characterized for WWAN radios (2G/3G/4G/5G mmW NR) to determine the power limit that corresponds to the exposure design target after accounting for all device design related uncertainties, i.e.,  $SAR_{Design\ Target}$  (< FCC SAR limit) for Sub-6 GHz radio and  $PD_{Design\ Target}$  (< FCC PD limit) for mmW radio. The SAR Characterization and PD Characterization are denoted as *SAR Char* and *PD Char*.

*SAR Char* and *PD Char* will be used as input for Qualcomm Smart Transmit to operate. Both *SAR Char* and *PD Char* will be loaded and stored in the EUT via the *Embedded File System* (EFS).

The EUT supports WLAN/BT radio(s) as well, but the WLAN/BT modem is not enabled with Qualcomm's Smart Transmit feature.

All Sub-6 GHz SAR data referenced within this report has been extracted from UL's SAR report: 13573777-S1.

## 2. SAR Characterization

*SAR Char* is generated to cover all radio configurations and usage scenarios that are reported in the initial FCC submission.

### 2.1. Worst-case SAR Determination

Based on FCC KDBs, in general, for a smartphone, the SAR evaluation is required for the exposure scenarios shown in Figure 2-1.

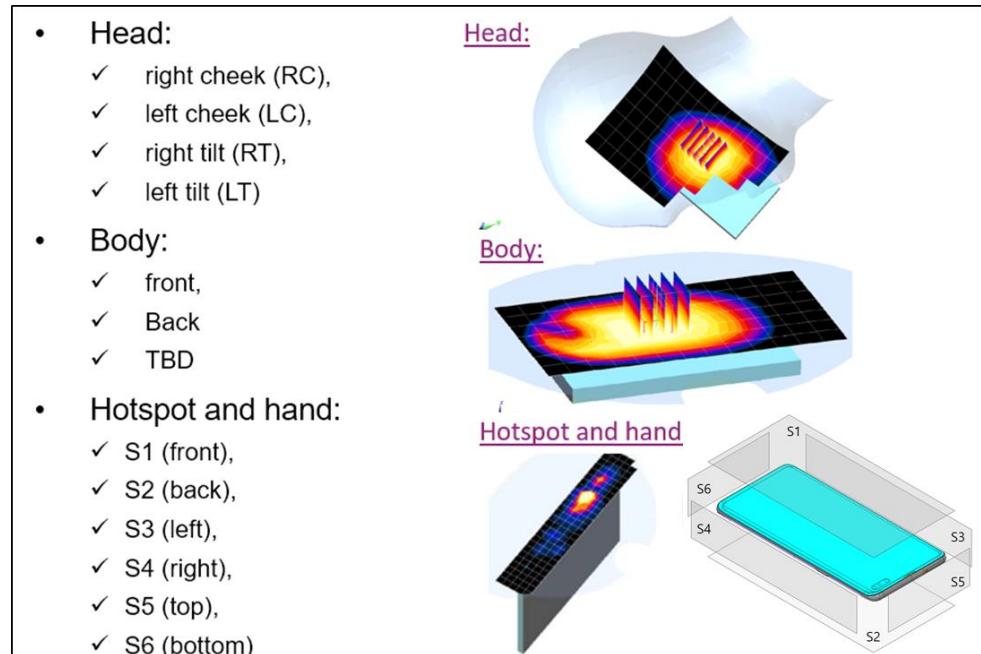


Figure 2-1: SAR evaluation for smartphone application

The *Device State Index* (DSI) used in Figure 2-2 represents each exposure scenario. Depending on the detection scheme implemented in the smartphone, the worst-case SAR is further grouped and determined for each or combined exposure scenario(s). Note, for the 1-g SAR versus 10-g SAR exposure scenario, the worst-case is determined in term of exposure ratio (i.e., exposure level relative to the corresponding 1-g or 10-g SAR limit).

- If the device does not have any detection mechanism (**all “no”** in Figure 2-2), then the worst-case SAR is determined by taking the maximum SAR value among all exposure scenarios, i.e., worst-case SAR =  $\max\{SAR_{head}, SAR_{body}, SAR_{hotspot/extremity}\}$
- If the device can distinguish each of the above scenarios (**all “yes”** in Figure 2-2), then the worst-case SAR for each individual exposure scenario is given by corresponding  $SAR_{head}$ ,  $SAR_{body}$ , and  $SAR_{hotspot/extremity}$
- If the device can only distinguish a subset of the scenarios (**some “yes”, some “no”** in Figure 2-2), then the worst-case SAR is given by:
  - Corresponding SAR for each exposure scenario that can be distinguished (DSI=yes)
  - Worst-case SAR among all other exposure scenario(s) that cannot be distinguished (DSI=no)

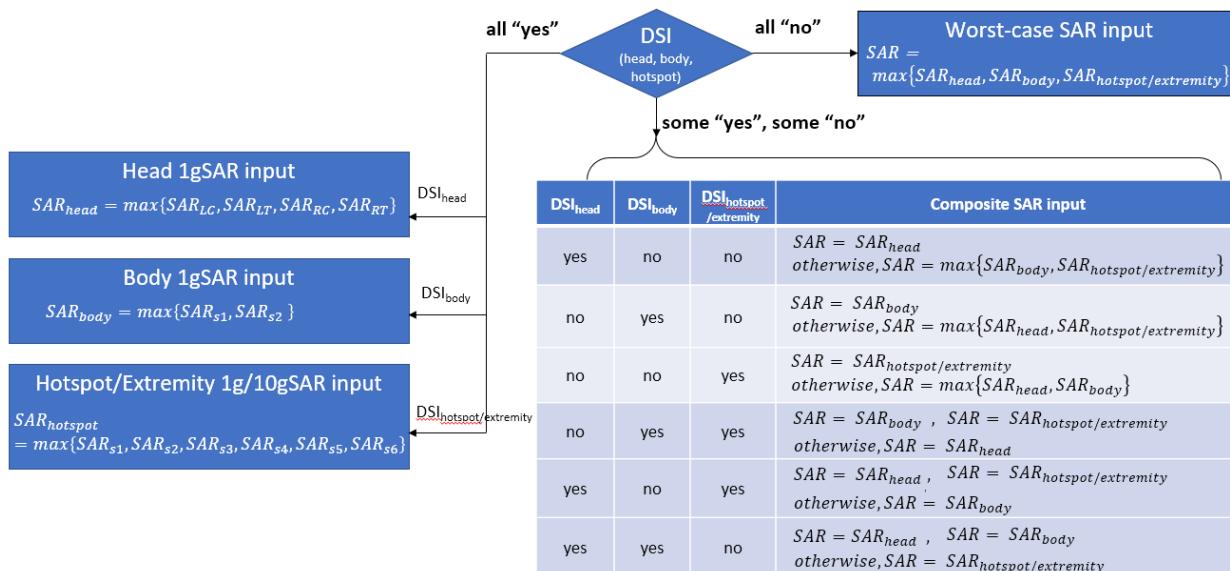


Figure 2-2: Worst-case SAR determination based on DSI

## 2.2. Usage Scenarios in SAR Evaluation

The EUT has a detection mechanism to distinguish Head, Body-worn, and Hotspot exposure conditions, which is represented using *DSI 0* and *1*. These *DSI* states were used to determine the power limit for Smart Transmit to operate; where the exposure scenario is managed as same *DSI* state, all other exposures which cannot be distinguished, in this particular instance and based on the worst-case SAR determination criteria described in §2.1, the maximum SAR (or the minimum  $P_{limit}$ ) among all remaining exposure scenarios (i.e., Body-worn 1-g SAR evaluation at a specified test separation distance, phablet extremity 10-g SAR evaluation at a specified test separation distance, and maximum RF tune-up power ( $P_{max}$ ) supported by the device if SAR measurement is not performed for this tech/band/antenna because of meeting SAR test exclusion criteria) is used to determine the power limit for Smart Transmit to operate.

The corresponding usage scenarios supported by EUT are summarized in Table 2-1:

Table 2-1: Usage/Exposure Scenario

Scenario	DSI State	Description	SAR Definition	Worst-case SAR
Head	0	<ul style="list-style-type: none"> <li>▪ Device positioned next to head</li> <li>▪ 1-g SAR evaluated in four positions (left/right touch/tilt)</li> </ul>	$SAR_{head} = \max \{SAR_{LC}, SAR_{LT}, SAR_{RC}, SAR_{RT}\}$	$SAR_{head}$
Body-worn/Hotspot	1	<ul style="list-style-type: none"> <li>▪ Device state is either Body-worn or Hotspot at 5 mm</li> <li>▪ 1-g SAR is evaluated for all six surfaces of the EUT (S1-S6 as shown in Figure 2-1) at 5 mm test separation distance relative to the flat phantom</li> </ul>	$SAR_{body\_DSI=1} = \max \{SAR_{body\_DSI=1}, SAR_{body\_DSI=1}, SAR_{body\_DSI=1}, SAR_{body\_DSI=1}, SAR_{body\_DSI=1}, SAR_{body\_DSI=1}\}$	$SAR_{body\_DSI=1}$

### 2.3. $SAR_{Design\ Target}$

The total device design and related uncertainties of the EUT is shown below (in dB), which includes TxAGC and device to device variation.

To account for the total uncertainty,  $SAR_{Design\ Target}$  needs to be:

$$SAR_{Design\ Target} < SAR_{Design\ Limit} \times 10^{\frac{-total\ uncertainty}{10}}$$

For the FCC SAR requirement of 1.6 W/kg and 4.0 W/kg, 1-g and 10-g SAR respectively, the  $SAR_{Design\ Target}$  for the EUT is determined as:

Total Uncertainty (dB)	$SAR_{Design\ Target}$ (1-g W/kg)	$SAR_{Design\ Target}$ (10-g W/kg)	$SAR_{Design\ Limit}$ (1-g W/kg)	$SAR_{Design\ Limit}$ (10-g W/kg)
1.00	0.8	2.0	1.0	2.5

## 2.4. SAR Characterization

Referring to the initial FCC submission, the worst-case *reported* SAR for each antenna/technology/band/DSI is summarized in Table 2-2:

**Table 2-2: Worst-case reported SAR**

Tech/Band	Antenna			Worst-case SAR (W/kg)			$P_{\text{limit}}$ Max Tune-up Power (dBm)		
	Head	Body-worn	Hotspot	Head	Body-worn	Hotspot	Head	Body-worn	Hotspot
	DSI: 0	DSI: 1	DSI: 1	DSI: 0	DSI: 1	DSI: 1	DSI: 0	DSI: 1	DSI: 1
GSM 850 2 slots	ANT2	ANT1	ANT1	0.535	0.792	0.792	31.00	32.50	32.50
GSM 1900 2 slots	ANT2	ANT3	ANT2	0.952	0.798	0.948	26.00	26.90	26.20
W-CDMA B2	ANT3	ANT3	ANT3	0.953	0.880	0.959	24.40	20.50	20.50
W-CDMA B4	ANT4	ANT1	ANT3	0.945	0.938	0.947	20.30	20.50	21.50
W-CDMA B5	ANT2	ANT1	ANT1	0.941	0.725	0.912	24.70	25.40	25.40
CDMA BC0	ANT2	ANT1	ANT1	0.764	0.432	0.625	22.00	22.50	22.50
CDMA BC1	ANT2	ANT1	ANT1	0.904	0.724	0.953	19.50	17.30	17.30
CDMA BC10	ANT2	ANT1	ANT1	0.928	0.726	0.901	24.70	25.40	25.40
LTE Band 5	ANT2	ANT1	ANT1	0.847	0.701	0.883	24.70	25.40	25.40
LTE Band 7	ANT2	ANT2	ANT1	0.917	0.903	0.927	18.20	19.00	20.50
LTE Band 12/17	ANT2	ANT2	ANT2	0.929	0.626	0.626	24.70	24.70	24.70
LTE Band 13	ANT2	ANT1	ANT1	0.772	0.596	0.868	24.70	25.70	25.70
LTE Band 14	ANT2	ANT1	ANT1	0.781	0.761	0.957	24.70	25.70	25.70
LTE Band 25/2	ANT4	ANT3	ANT1	0.949	0.922	0.959	19.60	20.50	17.30
LTE Band 26	ANT2	ANT1	ANT1	0.874	0.654	0.918	24.70	25.40	25.40
LTE Band 30	ANT2	ANT3	ANT3	0.957	0.953	0.953	19.60	19.70	19.70
LTE Band 41	ANT3	ANT3	ANT1	0.935	0.933	0.940	25.20	20.80	21.70
LTE Band 48	ANT8	ANT8	ANT7	0.957	0.955	0.956	21.50	23.00	21.90
LTE Band 66/4	ANT4	ANT1	ANT4	0.940	0.921	0.956	20.30	20.50	21.50
LTE Band 71	ANT2	ANT1	ANT1	0.725	0.697	0.697	24.70	25.70	25.70
NR n5	ANT2	ANT1	ANT1	0.510	0.457	0.540	24.70	25.40	25.40
NR n7	ANT3	ANT2	ANT2	0.843	0.878	0.878	23.70	19.00	19.00
NR n12	ANT2	ANT1	ANT1	0.571	0.475	0.521	24.70	25.70	25.70
NR n25/2	ANT4	ANT3	ANT4	0.897	0.778	0.918	19.60	20.50	22.00
NR n30	ANT4	ANT3	ANT3	0.887	0.931	0.931	18.80	19.70	19.70
NR n41	ANT3	ANT3	ANT3	0.826	0.757	0.757	23.30	18.80	18.80
NR n66	ANT2	ANT1	ANT1	0.903	0.941	0.941	17.60	20.50	20.50
NR n71	ANT2	ANT1	ANT1	0.380	0.385	0.385	24.70	25.70	25.70
NR n77	ANT8	ANT9	ANT7	0.957	0.955	0.955	19.50	20.00	19.30

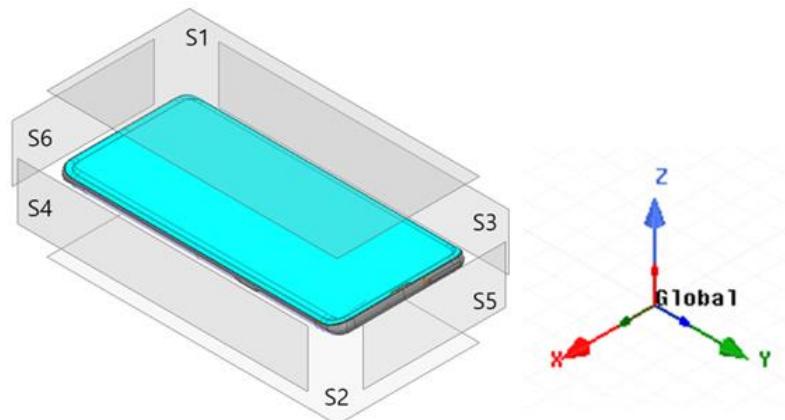




### 3.1. Exposure Scenarios in PD Evaluation

In general, for a smartphone operating at frequencies > 6 GHz, the PD is required to be assessed for all antenna configurations (beams) from all mmW antenna modules installed inside the device. Furthermore, this PD evaluation should be performed at low, mid, and high channels for each supported mmW band.

For this EUT, the 4cm<sup>2</sup> spatially-averaged PD is evaluated along the surfaces (*S1=front*, *S2=back*, *S3=left*, *S4=right*, *S5=top*, and *S6=bottom* as shown in Figure 3-1) and the worst-case PD is determined by taking the maximum PD among all the evaluated surfaces for each beam/band.



**Figure 3-1: EUT surface definition**

### 3.2. PD Characterization Overview

Parameters used in PD Characterization:

- The EUT supports a total of 135 beams per band, where 90 beams are single beams (SISO) and 45 are beam pairs (MIMO) where 2 single beams are excited at the same time.
- ***PD<sub>Design Target</sub>***: The design target for PD compliance as defined in the summary report. It should be less than the FCC PD limit to account for all device design related uncertainties.
- ***input.power.limit***: For a PD characterized wireless device, the input power level at antenna port(s) for each beam corresponding to *PD\_design\_target*.
- ***PD Characterization***: The table that contains the *input.power.limit* fed to antenna port(s) for all supported beams.

Figure 3-2 outlines the PD Char process.

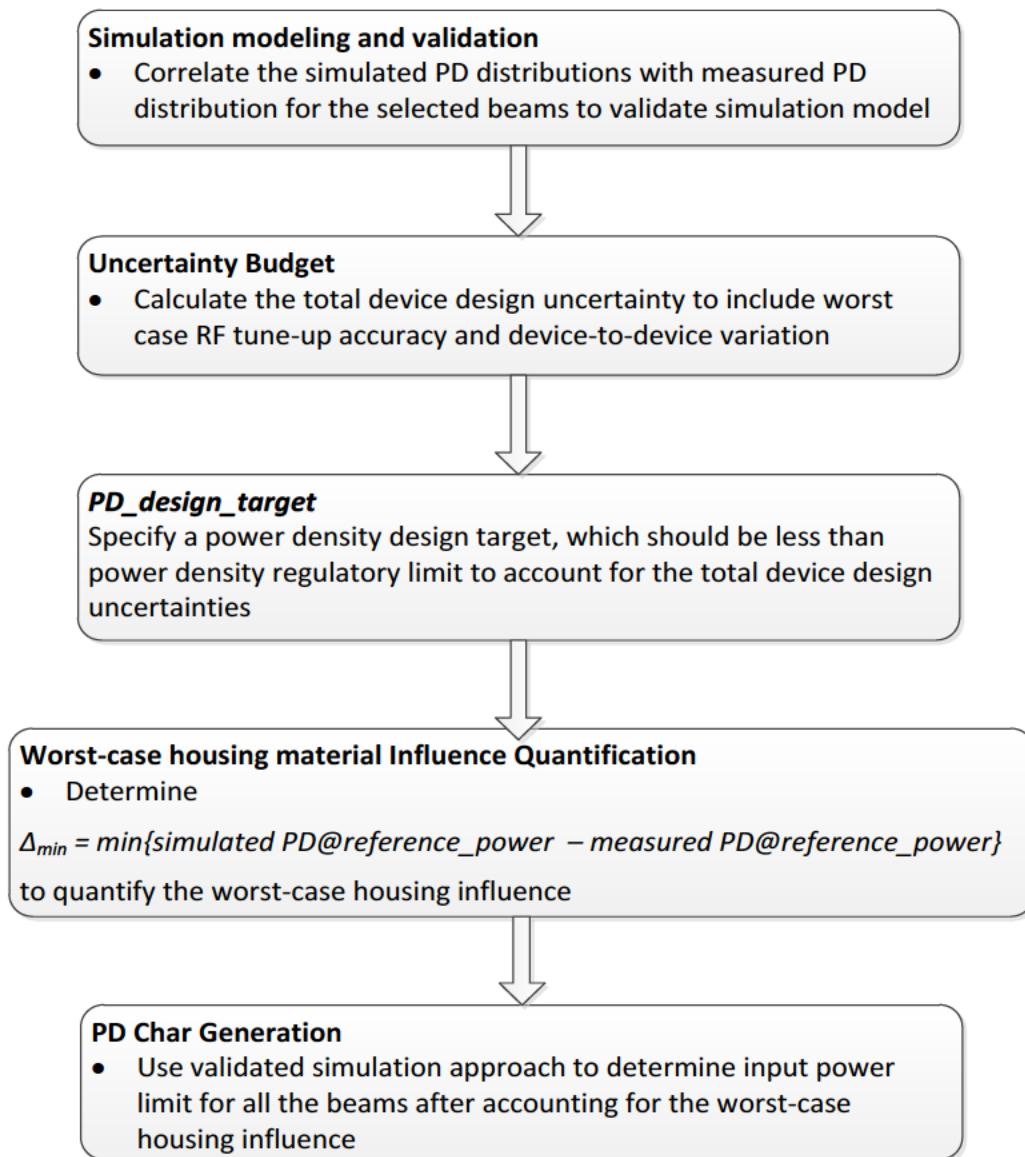


Figure 3-2 High level flow chart for power density characterization

### 3.3. EUT Codebook

In general, all the beams that the smartphone supports are specified in the pre-defined codebook. The codebook is device design specific and generated after evaluating radiation coverage from this specific device.

Table 3-1 shows all the beams and their relevant information.

The PD evaluation needs to be performed for all the beams listed in Table 3-1.

Table 3-1: EUT Codebook

Band	Beam ID	Paired With	Module	Ant Type	# of Elements	Band	Beam ID	Paired With	Module	Ant Type	# of Elements	Band	Beam ID	Paired With	Module	Ant Type	# of Elements
258	0	128	M1	PATCH	1	260	0	128	M1	PATCH	1	261	0	128	M1	PATCH	1
	1	129	M0	PATCH	1		1	129	M0	PATCH	1		1	129	M0	PATCH	1
	2	130	M2	PATCH	1		2	130	M2	PATCH	1		2	130	M2	PATCH	1
	3	131	M1	PATCH	1		3	131	M1	PATCH	1		3	131	M1	PATCH	1
	4	132	M0	PATCH	1		4	132	M0	PATCH	1		4	132	M0	PATCH	1
	5	133	M2	PATCH	1		5	133	M2	PATCH	1		5	133	M2	PATCH	1
	6	134	M1	PATCH	2		6	134	M1	PATCH	2		6	134	M1	PATCH	2
	7	135	M1	PATCH	2		7	135	M1	PATCH	2		7	135	M1	PATCH	2
	8	136	M1	PATCH	2		8	136	M1	PATCH	2		8	136	M1	PATCH	2
	9	137	M1	PATCH	2		9	137	M1	PATCH	2		9	137	M1	PATCH	2
	10	138	M0	PATCH	2		10	138	M0	PATCH	2		10	138	M0	PATCH	2



## 3.4. Simulation and modeling validation

### 3.4.1. Modeling for Simulation

Device modeling is described in the operational description.

### 3.4.2. Modeling Validation

To validate modeling and simulation:

1. Select one beam (i.e., antenna array configuration) per antenna type (dipole/patch) and per antenna module. All three antennas contain only patch arrays. Therefore, the beam selection criteria for each mmW antenna are:
  - a) Two beams from each antenna module.

Note: Since the relative phase between two single beams in a beam pair is uncontrolled and could vary from run to run, for the validation purpose, the selection is limited to the single beam antenna array configuration. Additionally, single beam containing a higher number of active antenna elements is selected. For example, a single beam with four active patches should be selected over beam with a single active patch antenna beam. The beams selected for modeling validation are highlighted in grey in Table 3-1.

2. For a given input power, perform both PD simulation and PD measurement to obtain the simulated PD distributions and measured PD distributions on the surface in front of the antenna array.
3. Validate modeling and simulation by correlating the simulated PD distribution and measured PD distribution for all antenna array configurations selected in Step 1 and for all surfaces selected in Step 2.
4. The modeling validation is performed through correlating the simulated 4 cm<sup>2</sup>-average PD distribution to measured 4 cm<sup>2</sup>-average PD distribution.
5. These discrepancies in PD magnitude will be used to determine the worst-case housing influence (due to non-metal material property uncertainty) in §4.6. The worst-case housing influence will be accounted for in PD Characterization generation for conservative RF exposure assessment, see §4.7 for details.

Based on the selection criteria described in Step 1 and Step 2, the beams and surfaces selected for modeling validation of the EUT are listed in Table 3-2.

**Table 3-2: Beams and surfaces selection for PD correlation**

<b>Band</b>	<b>Beam ID</b>	<b>Antenna</b>	<b>Pol</b>	<b>Surface</b>
n258	29	M1	V	Back
	167		H	Back
	21	M0	V	Back
	141		H	Back
	34	M2	V	Right
	162		H	Right
n260	39	M1	V	Back
	157		H	Back
	22	M0	V	Back
	140		H	Back
	43	M2	V	Right
	162		H	Right
n261	39	M1	V	Back
	157		H	Back
	22	M0	V	Back
	140		H	Back
	42	M2	V	Right
	171		H	Right

With an input power of 6.0 dBm (which will be referred to as  $P_{ref}$ ) for bands n258, n260, and n261PD measurement and PD simulation are conducted for all beams and surfaces listed in Table 3-2. Both PD measurement and PD simulation are performed at mid channel of each mmW beam, PD measurement is conducted with CW modulation.

- PD distribution:

Please refer to the operational description.

- 4cm<sup>2</sup>-averaged PD value

Table 3-3 lists the measured 4cm<sup>2</sup>-averaged PD and simulated 4cm<sup>2</sup>-averaged PD for all selected beams and surfaces for n258, n260, n261 bands. The discrepancy between simulated and measured PD value will be used to determine worst-case housing influence for conservative assessment (see §4.6).

**Table 3-3: Measured and simulated 4 cm<sup>2</sup> averaged PD for selected beams with 6 dBm input power for selected bands**

Band	Beam ID	Antenna	Pol	Surface	4cm <sup>2</sup> avg. PD (W/m <sup>2</sup> )		Delta <sup>1</sup>
					Meas.	Sim	
n258	29	M1	V	Back	12.50	13.62	<b>0.37</b>
	167		H	Back	10.00	23.02	<b>3.62</b>
	21	M0	V	Back	4.58	6.46	<b>1.49</b>
	141		H	Back	3.22	6.51	<b>3.06</b>
	34	M2	V	Right	10.50	20.39	<b>2.88</b>
	162		H	Right	13.50	18.15	<b>1.29</b>
n260	39	M1	V	Back	11.90	13.34	<b>0.50</b>
	157		H	Back	11.90	8.09	<b>-1.68</b>
	22	M0	V	Back	2.36	5.66	<b>3.80</b>
	140		H	Back	3.44	4.56	<b>1.22</b>
	43	M2	V	Right	11.30	15.37	<b>1.34</b>
	162		H	Right	16.00	16.26	<b>0.07</b>
n261	39	M1	V	Back	13.80	12.24	<b>-0.52</b>
	157		H	Back	9.44	22.21	<b>3.72</b>
	22	M0	V	Back	4.41	5.77	<b>1.17</b>
	140		H	Back	3.78	6.77	<b>2.53</b>
	42	M2	V	Right	16.00	20.77	<b>1.13</b>
	171		H	Right	16.10	18.57	<b>0.62</b>

<sup>1</sup>Delta = Sim - Meas (dB)

### 3.4.3. Simulation for power density

The model is validated in §4.4.3, the PD exposure of EUT can be reliably assessed using the validated simulation approach.

In general, all six surfaces of the EUT, as shown in Figure 3-1, should be assessed for RF exposure from the mmW radio and the worst-case PD should be determined by:

$$PD_{\text{worst-case}} = \max \{PD_{S1}, PD_{S2}, PD_{S3}, PD_{S4}, PD_{S5}, PD_{S6}\} \quad (1)$$

where  $PD_{S1}$ ,  $PD_{S2}$ ,  $PD_{S3}$ ,  $PD_{S4}$ ,  $PD_{S5}$ ,  $PD_{S6}$  are the highest 4cm<sup>2</sup>-averaged PD on surface S1, S2, S3, S4, S5 and S6 of the device, respectively.

However, depending on the location of the mmW module and the antenna array orientation relative to the surface of the device, one or more surface(s) can be excluded for PD calculation as the PD value(s) on the excluded surface(s) will be undoubtedly lower when comparing to other surfaces; thus, the exclusion will have no impact for the worst-case PD determined using Equation 1.

For this EUT, based on the location of M1, M0, and M2 (shown in the operational description) and the type of antenna array (containing in each a millimeter wave antenna), the surface planes identified for PD evaluation to determine the worst-case PD are selected and listed in Table 3-4.

**Table 3-4: PD evaluation plane**

n258	<b>Front</b>	<b>Back</b>	<b>Left</b>	<b>Right</b>	<b>Top</b>	<b>Bottom</b>
	<b>S1</b>	<b>S2</b>	<b>S3</b>	<b>S4</b>	<b>S5</b>	<b>S6</b>
<b>M1</b>	No	Yes	Yes	No	No	No
<b>M0</b>	No	Yes	Yes	No	Yes	No
<b>M2</b>	Yes	Yes	No	Yes	No	No

n260	<b>Front</b>	<b>Back</b>	<b>Left</b>	<b>Right</b>	<b>Top</b>	<b>Bottom</b>
	<b>S1</b>	<b>S2</b>	<b>S3</b>	<b>S4</b>	<b>S5</b>	<b>S6</b>
<b>M1</b>	No	Yes	Yes	No	No	No
<b>M0</b>	No	Yes	Yes	No	Yes	No
<b>M2</b>	Yes	Yes	No	Yes	No	No

n261	<b>Front</b>	<b>Back</b>	<b>Left</b>	<b>Right</b>	<b>Top</b>	<b>Bottom</b>
	<b>S1</b>	<b>S2</b>	<b>S3</b>	<b>S4</b>	<b>S5</b>	<b>S6</b>
<b>M1</b>	No	Yes	Yes	No	No	No
<b>M0</b>	No	Yes	Yes	No	Yes	No
<b>M2</b>	Yes	Yes	No	Yes	No	No

The EM simulation is performed to characterize PD at low, mid, and high channels for each supported band. The simulation setup (mesh, convergence criteria, and radiation boundary settings) as described in the operational description, ensures the accurate and reliable result for PD simulation on the planes identified. Both point PD and 4cm<sup>2</sup>-averaged PD distributions on the worst surface plane (i.e., the surface having highest PD value for the beam tested) are plotted and provided in the operational description to show that the PD hotspots are captured in this analysis.

### 3.5. PD<sub>Design Target</sub>

The manufacturer has their own internal controls for managing uncertainty and declared 2.20 dB uncertainty for use in determining the PD<sub>Design Target</sub> using Qualcomm's SDX-60M modem.

To account for the total design related uncertainty, PD<sub>Design Target</sub> needs to be:

$$PD_{Design\ Target} < PD_{Design\ Limit} \times 10^{\frac{-total\ uncertainty}{10}}$$

With FCC's 4cm<sup>2</sup>-averaged PD requirement of 10 W/m<sup>2</sup> and with the manufacturer's declared device design related uncertainty, the PD<sub>Design Target</sub> is determined as:

Total Uncertainty (dB)	PD <sub>Design Target</sub> (W/m <sup>2</sup> )	PD <sub>Design Limit</sub> (W/m <sup>2</sup> )
2.20	6.0	10.0

### 3.6. Worst-case Housing Influence Determination

For non-metal material, the material property cannot be accurately characterized at mmW frequencies to date. The estimated material property for the device housing is used in the simulation model, which could influence the accuracy in simulation for PD amplitude quantification. Since the housing influence on PD could vary from surface to surface where the EM field propagates through, the most underestimated surface is used to quantify the worst-case housing influence for conservative assessment.

Since the mmW antenna modules are placed at different locations, as shown in the operational description, only material/housing have an impact on EM field propagation, and, in turn, impact on power density. Furthermore, depending on the type of antenna array, i.e., dipole antenna array or patch antenna array, the nature of EM field propagation in the near field is different. Therefore, the worst-case housing influence is determined per antenna module and per antenna type.

For this EUT, when comparing a simulated 4cm<sup>2</sup>-averaged PD and measured 4 cm<sup>2</sup>-averaged PD, the worst error introduced for each type of antenna array and antenna module when using the estimated material property in the simulation is accented in bold numbers in Table 3-5. Thus, the worst-case housing influence, denoted as  $\Delta_{min} = \text{Sim. PD} - \text{Meas. PD}$ , is determined as:

**Table 3-5:  $\Delta_{min}$  for ANT M1, ANT M0, and ANT M2**

Band	Ant	Pol	$\Delta_{min}$ (dB)
n258	M1 (Patch Beam)	V	<b>0.37</b>
		H	<b>3.62</b>
	M0 (Patch Beam)	V	<b>1.49</b>
		H	<b>3.06</b>
	M2 (Patch Beam)	V	<b>2.88</b>
		H	<b>1.29</b>
n260	M1 (Patch Beam)	V	<b>0.50</b>
		H	<b>-1.68</b>
	M0 (Patch Beam)	V	<b>3.80</b>
		H	<b>1.22</b>
	M2 (Patch Beam)	V	<b>1.34</b>
		H	<b>0.07</b>
n261	M1 (Patch Beam)	V	<b>-0.52</b>
		H	<b>3.72</b>
	M0 (Patch Beam)	V	<b>1.17</b>
		H	<b>2.53</b>
	M2 (Patch Beam)	V	<b>1.13</b>
		H	<b>0.62</b>

$\Delta_{min}$  represents the worst case where RF exposure is underestimated the most in simulation when using the estimated material property for glass/plastics of the housing. For conservative assessment, the  $\Delta_{min}$  is used as the worst-case factor and applied to all the beams in the corresponding beam group to determine input power limits in PD char for compliance (see §4.7.3 for details).

### 3.7. PD Characterization

This section describes the PD Characterization generation that complies with the  $PD_{Design\ Target}$  determined in §4.5 and complies the regulatory power density limit.

#### 3.7.1. Scaling Factor for Single Beams

To determine the input power limit at each antenna port, perform the simulation at low, mid, and high channel for each mmW band supported, with a given input power per active port:

1. Obtain  $PD_{surface}$  value (the worst PD among all identified surfaces of the EUT) at all three channels for all single beams specified in the codebook of Table 3-1.
2. Derive a scaling factor at low, mid and high channel,  $s(i)_{low\_or\_mid\_or\_high}$ , by:

$$s(i)_{low\_or\_mid\_or\_high} = \frac{PD \text{ design target}}{\text{sim. } PD_{surface}(i)}, i \in \text{single beams} \quad (2)$$

3. Determine the worst-case scaling factor,  $s(i)$ , among low, mid and high channels:

$$s(i) = \min \{s_{low}(i), s_{mid}(i), s_{high}(i)\}, i \in \text{single beams} \quad (3)$$

and this scaling factor applies to the input power at each antenna port.

### 3.7.2. Scaling Factor for Beam Pairs

The relative phase between beam pair is not controlled in the EUT and could vary from run to run. Therefore, for a beam pair, based on the simulation results, the worst-case scaling factor needs to be determined mathematically to ensure compliance.

For a beam pair, extract the E-fields and H-fields from the corresponding single beams at low, mid, and high channel for each supported band and for all identified surfaces of the EUT.

For a given beam pair containing  $beam_a$  and  $beam_b$ , and for a given channel, let relative phase between  $beam_a$  and  $beam_b = \emptyset$ , and the total PD of the beam pair can be expressed as:

$$\begin{aligned} \text{total PD } (\emptyset) &= \frac{1}{2} \sqrt{\text{Re}\{PD_x(\emptyset)\}^2 + \text{Re}\{PD_y(\emptyset)\}^2 + \text{Re}\{PD_z(\emptyset)\}^2} \\ &= \frac{1}{2} \text{Re} \left\{ \left( \overrightarrow{E_a} + \overrightarrow{E_b e^{j\omega\emptyset}} \right) \times \left( \overrightarrow{H_a} + \overrightarrow{H_b e^{j\omega\emptyset}} \right)^* \right\} \quad (4) \end{aligned}$$

where,  $PD_x(\emptyset)$ ,  $PD_y(\emptyset)$ , and  $PD_z(\emptyset)$  are the three components of the total PD ( $\emptyset$ );  $E_a$  and  $H_a$  are the extracted E-fields and H-fields of  $beam_a$ , while  $E_b$  and  $H_b$  are the extracted E-fields and H-fields of  $beam_b$ .

Sweep  $\emptyset$  with a  $5^\circ$  step from  $0^\circ$  to  $360^\circ$  to determine the worst-case,  $\emptyset_{worstcase}$ , which results in the highest total PD ( $\emptyset$ ) among all identified surfaces for this beam pair at this channel. For details on the worst case total PD ( $\emptyset$ ) derivation, see Appendix A.

Follow the above procedure to determine  $\emptyset_{worstcase}$  for all three channels to obtain the scaling factor given by the equation below for low, mid, and high channels:

$$s(i)_{low\_or\_mid\_or\_high} = \frac{PD \text{ design target}}{\text{total PD } (\emptyset(i)_{worstcase})}, i \in \text{beam pairs} \quad (5)$$

The  $\emptyset_{worstcase}$  varies with channel and beam pair, the lowest scaling factor among all three channels,  $s(i)$ , is determined for the beam pair  $i$ :

$$s(i) = \min \{s_{low}(i), s_{mid}(i), s_{high}(i)\}, i \in \text{beam pairs} \quad (6)$$

### 3.7.3. Input Power Limit

The PD Characterization specifies the limit of input power at an antenna port that corresponds to  $PD_{Design \ Target}$  for all beams.

Ideally, if there is no uncertainty associated with hardware design, the input power limit, denoted as  $input.power.limit(i)$ , for beam  $i$  can be obtained after accounting for the housing influence ( $\Delta_{min}$ ) determined in Table 3-6 of §4.6, given by:

$$input.power.limit(i) = P_{ref} + 10 * \log(s(i)) + \Delta_{min}, i \in \text{all beams} \quad (7)$$

where  $P_{ref}$  is the input power using in simulation;  $s(i)$  is the scaling factor obtained from Eq. (3) or Eq. (6) for beam  $i$ ;  $\Delta_{min}$  is the worst-case housing influence factor (determined in Table 3-6) for beam  $i$ .

If simulation overestimates the housing influence, then  $\Delta_{min}$  (= simulated PD – measured PD) is negative, which means that the measured PD would be higher than the simulated PD. The input power to antenna elements determined via simulation must be decreased for compliance.

Similarly, if simulation underestimates the loss, then  $\Delta_{min}$  is positive (measured PD would be lower than the simulated value). Input power to antenna elements determined via simulation can be increased and still be PD compliant.

The hardware design has uncertainty which must be properly considered. In §4.6, the TxAGC uncertainty is embedded in the process of  $\Delta_{min}$  determination. Since TxAGC uncertainty is already accounted for in  $PD_{Design\ Target}$  (see §4.5), it needs to be removed to avoid double counting this uncertainty.

Thus, Equation 7 is modified to:

**If** -TxAGC uncertainty <  $\Delta_{min}$  < TxAGC uncertainty,

$$input.power.limit(i) = P_{ref} + 10 * \log(s(i)), i \in all\ beams \quad (8)$$

**else if**  $\Delta_{min}$  < -TxAGC uncertainty,

$$input.power.limit(i) = P_{ref} + 10 * \log(s(i)) + \Delta_{min}, i \in all\ beams \quad (9)$$

**else if**  $\Delta_{min}$  > TxAGC uncertainty,

$$input.power.limit(i) = P_{ref} + 10 * \log(s(i)) + (\Delta_{min} - \text{TxAGC uncertainty}), i \in all\ beams \quad (10)$$

Following the logic above, the *input.power.limit* for this EUT can be calculated using Equations (8), (9) and (10), i.e.,

**Table 3-6: *input.power.limit* calculation**

Band	Ant	Pol	$\Delta_{min}$ (dB)	<i>Input.power.limit</i> Equation (dBm)	Notes
n258	M1 (Patch Beam)	V	<b>0.37</b>	$6\text{ dBm} + 10 * \log(s(i))$	Using Eq. 8
		H	<b>3.62</b>	$6\text{ dBm} + 10 * \log(s(i)) + 2.62$	Using Eq. 10
	M0 (Patch Beam)	V	<b>1.49</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.49$	Using Eq. 10
		H	<b>3.06</b>	$6\text{ dBm} + 10 * \log(s(i)) + 2.06$	Using Eq. 10
	M2 (Patch Beam)	V	<b>2.88</b>	$6\text{ dBm} + 10 * \log(s(i)) + 1.88$	Using Eq. 10
		H	<b>1.29</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.29$	Using Eq. 10
n260	M1 (Patch Beam)	V	<b>0.50</b>	$6\text{ dBm} + 10 * \log(s(i))$	Using Eq. 8
		H	<b>-1.68</b>	$6\text{ dBm} + 10 * \log(s(i)) + -1.68$	Using Eq. 9
	M0 (Patch Beam)	V	<b>3.80</b>	$6\text{ dBm} + 10 * \log(s(i)) + 2.8$	Using Eq. 10
		H	<b>1.22</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.22$	Using Eq. 10
	M2 (Patch Beam)	V	<b>1.34</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.34$	Using Eq. 10
		H	<b>0.07</b>	$6\text{ dBm} + 10 * \log(s(i))$	Using Eq. 8
n261	M1 (Patch Beam)	V	<b>-0.52</b>	$6\text{ dBm} + 10 * \log(s(i))$	Using Eq. 8
		H	<b>3.72</b>	$6\text{ dBm} + 10 * \log(s(i)) + 2.72$	Using Eq. 10
	M0 (Patch Beam)	V	<b>1.17</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.17$	Using Eq. 10
		H	<b>2.53</b>	$6\text{ dBm} + 10 * \log(s(i)) + 1.53$	Using Eq. 10
	M2 (Patch Beam)	V	<b>1.13</b>	$6\text{ dBm} + 10 * \log(s(i)) + 0.13$	Using Eq. 10
		H	<b>0.62</b>	$6\text{ dBm} + 10 * \log(s(i))$	Using Eq. 8

Thus, the EUT PD Char for n258, n260, and n261 bands are as shown in Table 3-7.

Table 3-7: PD Characterization

n258			n260			n261		
Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)
N/A	0	6.9	N/A	0	7.6	N/A	0	7.5
	1	9.2		1	11.6		1	8.8
	2	8.7		2	7.2		2	6.9
	3	5.6		3	8.0		3	5.9
	4	9.0		4	11.8		4	9.0
	5	7.8		5	7.2		5	5.7
	6	3.0		6	3.9		6	2.9
	7	2.8		7	6.2		7	4.3
	8	3.5		8	4.4		8	7.2
	9	2.4		9	5.9		9	4.3
	10	6.2		10	9.0		10	6.5
	11	6.1		11	9.1		11	6.2
	12	6.0		12	8.8		12	6.0
	13	6.1		13	8.6		13	5.4
	14	4.7		14	4.4		14	3.6
	15	5.0		15	4.3		15	3.9
	16	4.5		16	4.9		16	3.5
	17	5.4		17	5.9		17	3.0
	18	3.2		18	6.7		18	4.1
	19	6.4		19	4.7		19	4.1
	20	3.6		20	4.3		20	3.6
	21	6.2		21	9.1		21	6.7
	22	6.0		22	9.1		22	6.3
	23	6.0		23	8.6		23	5.6
	24	5.4		24	5.0		24	2.8
	25	4.5		25	4.9		25	2.9
	26	4.5		26	6.1		26	3.5
	27	-0.5		27	1.2		27	-0.7
	28	0.5		28	1.5		28	0.4
	29	2.4		29	1.8		29	1.0
	30	0.8		30	2.8		30	2.5
	31	-0.3		31	4.7		31	0.7
	32	1.8		32	2.5		32	0.1
	33	2.1		33	2.0		33	0.6
	34	2.6		34	1.7		34	0.8
	35	2.4		35	3.0		35	0.4
	36	1.7		36	2.7		36	0.1
	37	-0.4		37	1.0		37	-0.4
	38	1.6		38	1.7		38	0.5
	39	1.8		39	2.5		39	2.9
	40	0.6		40	4.0		40	1.4
	41	1.9		41	2.4		41	0.1
	42	2.6		42	1.7		42	0.7
	43	2.6		43	2.3		43	0.8
	44	1.9		44	2.9		44	-0.1
	128	9.9		128	7.4		128	10.4
	129	9.7		129	10.0		129	9.3
	130	6.2		130	7.0		130	5.5

n258			n260			n261		
Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)
N/A	131	8.1	N/A	131	6.6	N/A	131	9.0
	132	10.6		132	10.2		132	10.5
	133	7.1		133	6.5		133	5.5
	134	5.6		134	5.3		134	6.0
	135	6.1		135	4.5		135	6.8
	136	5.5		136	2.8		136	6.4
	137	6.2		137	3.3		137	5.9
	138	7.6		138	7.4		138	7.2
	139	7.3		139	7.5		139	6.9
	140	7.0		140	7.4		140	7.0
	141	7.7		141	6.9		141	7.0
	142	3.6		142	4.4		142	2.9
	143	3.9		143	4.6		143	3.6
	144	3.8		144	4.2		144	3.1
	145	3.6		145	3.8		145	2.7
	146	5.4		146	2.7		146	8.0
	147	6.4		147	4.5		147	6.9
	148	6.1		148	2.8		148	6.4
	149	7.5		149	7.5		149	7.1
	150	7.1		150	7.6		150	6.8
	151	7.4		151	7.0		151	6.9
	152	3.1		152	4.4		152	2.9
	153	3.7		153	4.4		153	3.7
	154	3.8		154	4.3		154	3.0
	155	3.5		155	-0.1		155	5.4
	156	3.7		156	0.8		156	4.6
	157	2.6		157	3.0		157	3.0
	158	2.9		158	0.5		158	2.6
	159	5.9		159	0.1		159	4.8
	160	-0.1		160	1.7		160	0.1
	161	1.2		161	2.7		161	0.7
	162	1.5		162	1.7		162	1.0
	163	1.6		163	1.7		163	0.7
	164	0.6		164	2.0		164	-0.1
	165	3.8		165	1.3		165	5.8
	166	2.6		166	0.8		166	4.0
	167	2.8		167	2.8		167	2.7
	168	4.2		168	-0.6		168	3.0
	169	0.5		169	2.6		169	0.0
	170	1.5		170	1.8		170	1.0
	171	1.5		171	1.5		171	1.1
	172	1.2		172	2.0		172	0.0
128	0	3.9	128	0	3.5	128	0	4.3
129	1	5.3	129	1	5.9	129	1	4.9
130	2	3.5	130	2	3.5	130	2	3.0
131	3	2.6	131	3	3.0	131	3	2.7
132	4	5.8	132	4	6.4	132	4	5.7
133	5	3.3	133	5	3.5	133	5	2.3
134	6	1.0	134	6	0.6	134	6	-0.4
135	7	0.0	135	7	1.2	135	7	0.9
136	8	0.0	136	8	-0.3	136	8	1.9
137	9	-0.4	137	9	0.7	137	9	0.9
138	10	2.5	138	10	3.6	138	10	2.3
139	11	2.5	139	11	3.8	139	11	2.7

n258			n260			n261		
Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)	Paired ID (Beam Pair)	Beam ID	Input Power Limit (dBm)
140	12	2.5	140	12	3.3	140	12	2.6
141	13	2.9	141	13	2.9	141	13	2.5
142	14	0.4	142	14	0.6	142	14	0.2
143	15	0.2	143	15	1.4	143	15	0.9
144	16	0.4	144	16	1.5	144	16	-0.1
145	17	0.3	145	17	2.0	145	17	-0.3
146	18	-0.1	146	18	0.6	146	18	1.3
147	19	1.8	147	19	0.6	147	19	0.9
148	20	0.4	148	20	-0.2	148	20	0.4
149	21	2.6	149	21	3.7	149	21	2.8
150	22	2.5	150	22	3.7	150	22	2.7
151	23	2.8	151	23	3.0	151	23	2.5
152	24	0.7	152	24	1.2	152	24	-0.7
153	25	0.1	153	25	0.9	153	25	-0.3
154	26	-0.4	154	26	1.1	154	26	0.2
155	27	-1.9	155	27	-3.7	155	27	-2.2
156	28	-2.4	156	28	-2.9	156	28	-2.2
157	29	-2.2	157	29	-2.0	157	29	-2.9
158	30	-2.7	158	30	-2.1	158	30	-2.4
159	31	-2.1	159	31	-1.9	159	31	-2.3
160	32	-3.3	160	32	-1.1	160	32	-3.5
161	33	-2.8	161	33	-1.8	161	33	-2.9
162	34	-2.2	162	34	-2.2	162	34	-2.6
163	35	-2.2	163	35	-1.1	163	35	-3.0
164	36	-3.0	164	36	-1.3	164	36	-3.5
165	37	-2.5	165	37	-3.1	165	37	-2.2
166	38	-2.5	166	38	-2.9	166	38	-2.8
167	39	-2.4	167	39	-1.4	167	39	-2.0
168	40	-2.2	168	40	-2.4	168	40	-2.9
169	41	-3.0	169	41	-1.4	169	41	-3.6
170	42	-2.4	170	42	-2.1	170	42	-2.7
171	43	-2.1	171	43	-1.9	171	43	-2.5
172	44	-2.8	172	44	-0.9	172	44	-3.6

## A Worst Phase Derivation for Beam Pair

For beam pairs, since the relative phase between two beams is unknown, finding the worst-case PD by sweeping the relative phase for all possible angles is required for conservative assessment.

Assuming E-field and H-field of *beam<sub>a</sub>* are {*Ex<sub>a</sub>*, *Ey<sub>a</sub>*, *Ez<sub>a</sub>*} and {*Hx<sub>a</sub>*, *Hy<sub>a</sub>*, *Hz<sub>a</sub>*}, respectively; E-field and H-field of *beam<sub>b</sub>* are {*Ex<sub>b</sub>*, *Ey<sub>b</sub>*, *Ez<sub>b</sub>*} and {*Hx<sub>b</sub>*, *Hy<sub>b</sub>*, *Hz<sub>b</sub>*}, respectively; and the relative phase is  $\emptyset$ , for beam pair consisting of *beam<sub>a</sub>* and *beam<sub>b</sub>*, the combined E- and H-fields, {*Ex<sub>pair\_i</sub>*, *Ey<sub>pair\_i</sub>*, *Ez<sub>pair\_i</sub>*} and {*Hx<sub>pair\_i</sub>*, *Hy<sub>pair\_i</sub>*, *Hz<sub>pair\_i</sub>*}, can be expressed as:

$$\begin{aligned} Ex(\emptyset)_{pair_i} &= E_{x,a} + E_{x,b} \times e^{-j\omega\emptyset} \\ Ey(\emptyset)_{pair_i} &= E_{y,a} + E_{y,b} \times e^{-j\omega\emptyset} \\ Ez(\emptyset)_{pair_i} &= E_{z,a} + E_{z,b} \times e^{-j\omega\emptyset} \end{aligned}$$

$$\begin{aligned} Hx(\emptyset)_{pair_i} &= H_{x,a} + H_{x,b} \times e^{-j\omega\emptyset} \\ Hy(\emptyset)_{pair_i} &= H_{y,a} + H_{y,b} \times e^{-j\omega\emptyset} \\ Hz(\emptyset)_{pair_i} &= H_{z,a} + H_{z,b} \times e^{-j\omega\emptyset} \end{aligned}$$

The combined PD can then be calculated:

$$\begin{aligned} PDx(\emptyset)_{pair_i} &= Ey(\emptyset)_{pair_i} \times Hz(\emptyset)_{pair_i}^* - Ez(\emptyset)_{pair_i} \times Hy(\emptyset)_{pair_i}^* \\ PDy(\emptyset)_{pair_i} &= Ez(\emptyset)_{pair_i} \times Hx(\emptyset)_{pair_i}^* - Ex(\emptyset)_{pair_i} \times Hz(\emptyset)_{pair_i}^* \\ PDz(\emptyset)_{pair_i} &= Ex(\emptyset)_{pair_i} \times Hy(\emptyset)_{pair_i}^* - Ey(\emptyset)_{pair_i} \times Hx(\emptyset)_{pair_i}^* \\ PD(\emptyset) &= \frac{1}{2} \sqrt{Re\{PDx(\emptyset)\}_{pair_i}^2 + Re\{PDy(\emptyset)\}_{pair_i}^2 + Re\{PDz(\emptyset)\}_{pair_i}^2} \end{aligned}$$

Sweep  $\emptyset$  from 0 degree to 360 degree to find the highest PD (out of low, mid, and high channel) and its corresponding  $\emptyset$ ,  $\emptyset_{worstcase}$ , for all the beam pairs specified in the *codebook\_sim*. The worst-case scaling factor *s(i)* for beam pair should be determined with  $\emptyset(i)_{worstcase}$ .



